INFORMATION DISCLOSURE
CITATION IN AN
APPLICATION

ATTY. DOCKET NO. U.S. APPLICATION NO. **HEI-004 APPLICANT** Tsutomu IWASAKI et al.

FILING DATE **GROUP** herewith (PTO-1449) U.S. PATENT DOCUMENTS **EXAMINER'S** FILING PATENT NO. INITIALS DATE NAME **CLASS SUBCLASS** DATE FOREIGN PATENT DOCUMENTS 1 **EXAMINER'S CLASS SUBCLASS** PATENT NO. . DATE COUNTRY INITIALS /EL/ 0 344 331 12/06/1989 X Europe X 1 213 125 06/12/2002 Europe X 04-14430 01/20/1992 Japan X 04-301429 10/26/1992 Japan X 2001-139014 05/22/2001 Japan X 58-89319 05/27/1983 Japan 59-23536 06/02/1984 X Japan X 50-71576 11/07/1973 Japan X 12/27/1968 43-32236 Japan OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED **EXAMINER** /Edmund Lee/

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ATTY. DOCKET NO. HEI-004

**U.S. PATENT** APPLICATION NO. 10/521,594

**APPLICANT** 

Tsutomu IWASAKI et al

	(PTO-1	1449)	FILING DATE 01/18/2005			GROUP 1733	
		U.S. PA	TENT DOCUMENTS				
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
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/Edmund Lee/			DATE CONSIDER	DATE CONSIDERED 10/15/2007			

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